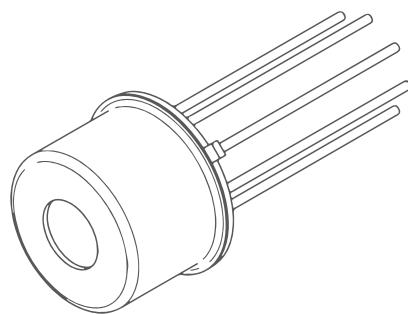


PVMA-1TE-5-1x1-TO39-pSiAR-70



InAsSb one-stage thermoelectrically cooled photovoltaic multi-junction infrared detector

FEATURES

- Spectral range: 1.7 to 5.5 μm
- RoHS-compliant III-V material
- Back-side illuminated
- No minimum order quantity required

RELATED PRODUCT

- **AMS3140-01** RoHS-compliant detection module (p. 86)

APPLICATIONS

- Contactless temperature measurement: railway transport, industrial and laboratory processes monitoring
- Flame and explosion detection
- Threat warning systems
- Heat-seeking, thermal signature detection
- Dentistry
- Gas detection, monitoring and analysis: CH_4 , C_2H_2 , CH_2O , HCl , NH_3 , SO_2 , C_2H_6 , CO , CO_2 , NO_x
- Breath analysis: C_2H_6 , CH_2O , NH_3 , NO , OCS
- Gas leak detection
- Combustion process control
- Non-destructive material testing

DETECTOR CONFIGURATION

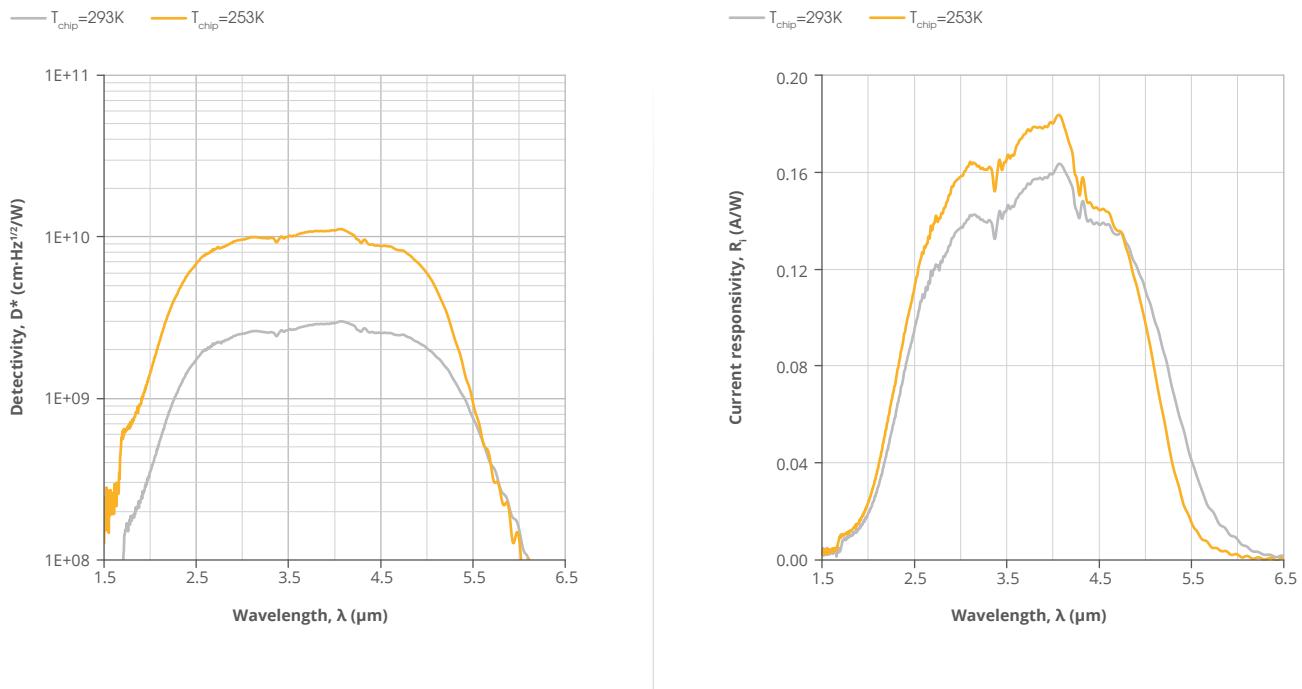
Detector symbol	Cooling (p. 191)	Temperature sensor (p. 192)	Active area, A, mm \times mm	Optical immersion	Package	Acceptance angle, Φ , deg.	Window (p. 193)
PVMA-1TE-5-1x1-TO39-pSiAR-70	1TE ($T_{\text{chip}} \leq 253\text{K}$)	theristor	1x1	no	TO39 (8 pins)	~70	pSiAR (planar silicon, anti-reflection coating)

SPECIFICATION ($T_{\text{amb}} = 293\text{ K}$, $V_b = 0\text{ V}$)

Detector symbol	Active element temperature				Cut-on wavelength (10%)		Peak wavelength		Cut-off wavelength (10%)		Detectivity		Current responsivity		Time constant		Dynamic resistance	
	T_{chip}	$\lambda_{\text{cut-on}}$	λ_{peak}	$\lambda_{\text{cut-off}}$														
	K	μm	μm	μm	$\text{cm}\cdot\text{Hz}^{1/2}/\text{W}$		A/W		ns									
	Typ.	Typ.	Typ.	Typ.	Min.	Typ.	Min.	Typ.	Typ.	Max.	Min.	Typ.						
PVMA-1TE-5-1x1-TO39-pSiAR-70	253	2.0	4.0±0.5	5.5	3.0×10^9	1.0×10^{10}	0.08	0.18	20	80	1 000	4 000						
	293			5.9	1.0×10^9	3.0×10^9	0.06	0.16	30	160	150	450						



SPECTRAL RESPONSE (Typ., $T_{\text{amb}} = 293 \text{ K}$)



MECHANICAL LAYOUT AND PINOUT

- 1TE-TO39 (8 pins) package – Technical drawing (p. 200)

ABSOLUTE MAXIMUM RATINGS

Parameter	Test conditions/remarks	Value	Unit
Ambient operating temperature, T_{amb}	Operation at $T_{\text{amb}} > 30^\circ\text{C}$ may increase the active element temperature and reduce the performance of the detector below specified parameters	-20 to 70	°C
Storage temperature, T_{stg}		-20 to 85	°C
Soldering temperature	Within 5 s or less	≤ 370	°C
Storage humidity	No dew condensation	10 to 90	%
Maximum incident optical power density	Continuous wave (CW) or single pulses >1 μs duration	100	W/cm ²
	Single pulses <1 μs duration	1	MW/cm ²
Maximum bias voltage, $V_{\text{b max}}$		-2	V
Maximum TEC voltage, $V_{\text{TEC max}}$	1TE	0.4	V
Maximum TEC current, $I_{\text{TEC max}}$	1TE	1.67	A

Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. Constant or repeated exposure to absolute maximum rating conditions may affect the quality and reliability of the device.